

ABSTRACT OF THE DISCLOSURE

A system for WAT (Wafer Acceptance Test) configuration.

The system comprises an input/output device, a storage device,

and a processor. The input/output device receives a first WAT

5 model and qualification criteria. The storage device stores a

preset WAT model and qualification criteria. The processor

modifies the preset WAT model according to the first WAT model

to generate a second WAT model, and modifies the preset

qualification criteria according to the first qualification

10 criteria to generate second qualification criteria.